

<b>Notice of References Cited</b>	Application/Control No. 10/000,177		Applicant(s)/Patent Under Reexamination TERASHIMA ET AL.	
	Examiner David E. Graybill		Art Unit 2822	Page 1 of 3

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<b>Notice of References Cited</b>	Application/Control No. 10/000,177	Applicant(s)/Patent Under Reexamination TERASHIMA ET AL.	
	Examiner David E. Graybill	Art Unit 2822	Page 2 of 3

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	Examiner David E. Graybill	Art Unit 2822	Page 3 of 3

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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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